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DISCRETE SEMICONDUCTORS

DATA SHEET

BF1211; BF1211R; BF1211WR N-channel dual-gate MOS-FETs

Product specification



N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

FEATURES

- Short channel transistor with high forward transfer admittance to input capacitance ratio
- · Low noise gain controlled amplifier
- Excellent low frequency noise performance
- Partly internal self-biasing circuit to ensure good cross-modulation performance during AGC and good DC stabilization.

APPLICATIONS

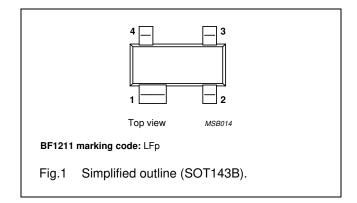
 Gain controlled low noise VHF and UHF amplifiers for 5 V digital and analog television tuner applications.

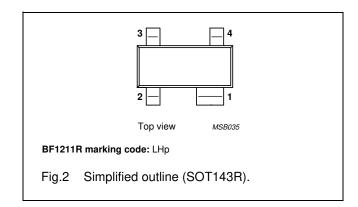
DESCRIPTION

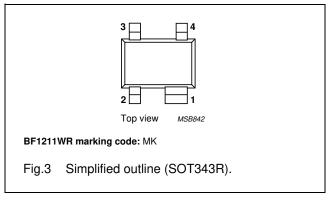
Enhancement type N-channel field-effect transistor with source and substrate interconnected. Integrated diodes between gates and source protect against excessive input voltage surges. The BF1211, BF1211R and BF1211WR are encapsulated in the SOT143B, SOT143R and SOT343R plastic packages respectively.

PINNING

PIN	DESCRIPTION
1	source
2	drain
3	gate 2
4	gate 1







QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V _{DS}	drain-source voltage		_	_	6	V
I _D	drain current		_	_	30	mA
P _{tot}	total power dissipation		-	=	180	mW
y _{fs}	forward transfer admittance		25	30	40	mS
C _{ig1-ss}	input capacitance at gate 1		_	2.1	2.6	pF
C _{rss}	reverse transfer capacitance	f = 1 MHz	_	15	30	fF
F	noise figure	f = 400 MHz	_	0.9	1.6	dB
X _{mod}	cross-modulation	input level for k = 1% at 40 dB AGC	100	105	_	dBμV
Tj	junction temperature		_	_	150	°C

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

CAUTION

This product is supplied in anti-static packing to prevent damage caused by electrostatic discharge during transport and handling.

ORDERING INFORMATION

TYPE NUMBER	PACKAGE							
TIPE NOWIBER	NAME	NAME DESCRIPTION						
BF1211	-	plastic surface mounted package; 4 leads	SOT143B					
BF1211R	_	plastic surface mounted package; reverse pinning; 4 leads	SOT143R					
BF1211WR	_	plastic surface mounted package; reverse pinning; 4 leads	SOT343R					

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DS}	drain-source voltage		_	6	٧
I _D	drain current (DC)		_	30	mA
I _{G1}	gate 1 current		-	±10	mA
I _{G2}	gate 2 current		_	±10	mA
P _{tot}	total power dissipation				
	BF1211; BF1211R	$T_s \le 116 ^{\circ}C$; note 1	_	180	mW
	BF1211WR	$T_s \le 122 ^{\circ}C$; note 1	_	180	mW
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		_	150	°C

Note

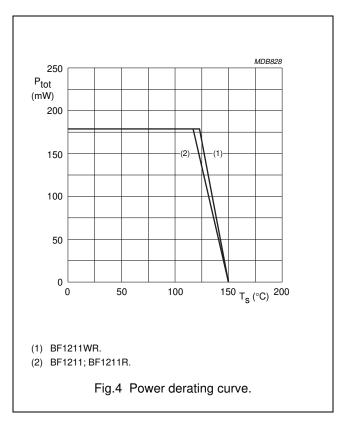
THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	VALUE	UNIT
R _{th(j-s)}	thermal resistance from junction to soldering point		
	BF1211; BF1211R	185	K/W
	BF1211WR	155	K/W

^{1.} T_s is the temperature of the soldering point of the source lead.

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR



STATIC CHARACTERISTICS

 T_j = 25 °C unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{G1-S} = V_{G2-S} = 0 \text{ V; } I_D = 10 \mu\text{A}$	6	_	٧
V _{(BR)G1-SS}	gate 1-source breakdown voltage	$V_{G2-S} = V_{DS} = 0 \text{ V}; I_{G1-S} = 10 \text{ mA}$	6	10	V
$V_{(BR)G2-SS}$	gate 2-source breakdown voltage	$V_{G1-S} = V_{DS} = 0 \text{ V}; I_{G2-S} = 10 \text{ mA}$	6	10	V
V _{(F)S-G1}	forward source-gate 1 voltage	$V_{G2-S} = V_{DS} = 0 \text{ V}; I_{S-G1} = 10 \text{ mA}$	0.5	1.5	V
$V_{(F)S-G2}$	forward source-gate 2 voltage	$V_{G1-S} = V_{DS} = 0 \text{ V}; I_{S-G2} = 10 \text{ mA}$	0.5	1.5	V
V _{G1-S(th)}	gate 1-source threshold voltage	$V_{G2-S} = 4 \text{ V}; V_{DS} = 5 \text{ V}; I_D = 100 \mu\text{A}$	0.3	1	V
V _{G2-S(th)}	gate 2-source threshold voltage	$V_{G1-S} = 5 \text{ V}; V_{DS} = 5 \text{ V}; I_D = 100 \mu\text{A}$	0.35	1	V
I _{DSX}	drain-source current	$V_{G2-S} = 4 \text{ V}; V_{DS} = 5 \text{ V}; R_{G1} = 75 \text{ k}\Omega;$ note 1	11	19	mA
I _{G1-S}	gate 1 cut-off current	$V_{G2-S} = V_{DS} = 0 \text{ V}; V_{G1-S} = 5 \text{ V}$	_	50	nA
I _{G2-S}	gate 2 cut-off current	$V_{G1-S} = V_{DS} = 0 \text{ V}; V_{G2-S} = 4 \text{ V}$	_	20	nA

Note

1. R_{G1} connects G_1 to V_{GG} = 5 V.

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

DYNAMIC CHARACTERISTICS

Common source; T_{amb} = 25 °C; V_{G2-S} = 4 V; V_{DS} = 5 V; I_D = 15 mA; unless otherwise specified.

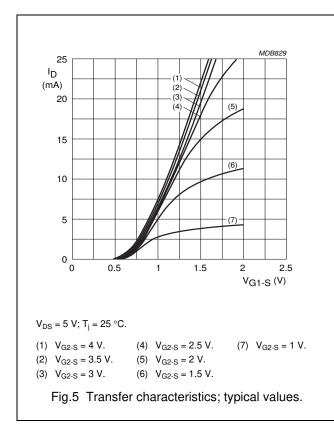
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
y _{fs}	forward transfer admittance	pulsed; T _j = 25 °C	25	30	40	mS
C _{ig1-ss}	input capacitance at gate 1	f = 1 MHz	_	2.1	2.6	pF
C _{ig2-ss}	input capacitance at gate 2	f = 1 MHz	_	1.1	_	pF
C _{oss}	output capacitance	f = 1 MHz	_	0.9	_	pF
C _{rss}	reverse transfer capacitance	f = 1 MHz	_	15	30	fF
F	noise figure	$f = 11 \text{ MHz}; G_S = 20 \text{ mS}; B_S = 0$	_	3.5	_	dB
		$f = 400 \text{ MHz}; Y_S = Y_{S \text{ (opt)}}$	_	0.9	1.6	dB
		$f = 800 \text{ MHz}; Y_S = Y_{S \text{ (opt)}}$	_	1.3	2	dB
G _{tr}	power gain	$f = 200 \text{ MHz}; G_S = 2 \text{ mS}; B_S = B_{S \text{ (opt)}};$ $G_L = 0.5 \text{ mS}; B_L = B_{L \text{ (opt)}}$	_	34	_	dB
		$f = 400 \text{ MHz}; G_S = 2 \text{ mS}; B_S = B_{S \text{ (opt)}};$ $G_L = 1 \text{ mS}; B_L = B_{L \text{ (opt)}}$	_	29	_	dB
		$ f = 800 \text{ MHz}; G_S = 3.3 \text{ mS}; B_S = B_{S \text{ (opt)}}; \\ G_L = 1 \text{ mS}; B_L = B_{L \text{ (opt)}} $	_	24	_	dB
X _{mod}	cross-modulation	input level for k = 1%; f _w = 50 MHz; f _{unw} = 60 MHz; note 1				
		at 0 dB AGC	90	_	_	$dB\mu V$
		at 10 dB AGC	_	92	_	$dB\mu V$
		at 40 dB AGC	100	105	_	dBμV

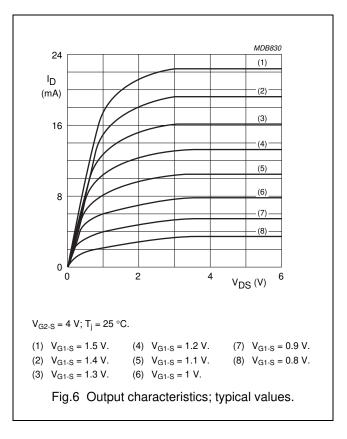
Note

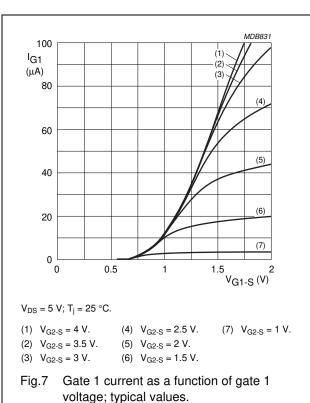
1. Measured in test circuit Fig.21.

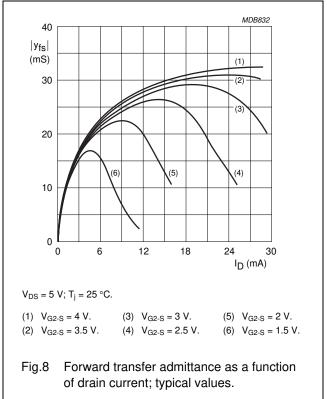
N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR



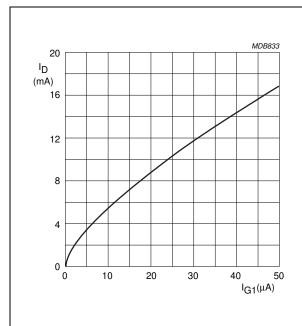






N-channel dual-gate MOS-FETs

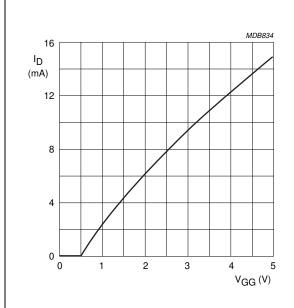
BF1211; BF1211R; BF1211WR



 $V_{DS} = 5 \text{ V}; V_{G2-S} = 4 \text{ V}.$

 $T_j = 25 \, ^{\circ}C$.

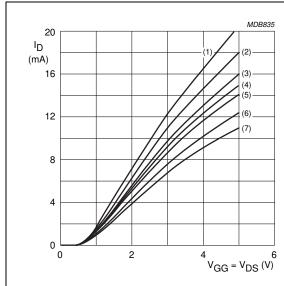
Fig.9 Drain current as a function of gate 1 current; typical values.



 V_{DS} = 5 V; $V_{G2\text{-}S}$ = 4 V; T_{j} = 25 °C.

 R_{G1} = 75 $k\Omega$ (connected to $V_{GG});$ see Fig.21.

Fig.10 Drain current as a function of gate 1 supply voltage (V_{GG}) ; typical values.

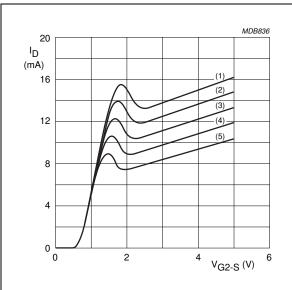


 $V_{G2-S} = 4 \text{ V}$; $T_i = 25 \,^{\circ}\text{C}$; R_{G1} connected to V_{GG} ; see Fig.21.

- (1) $R_{G1} = 47 \text{ k}\Omega$.
- (4) $R_{G1} = 75 \text{ k}\Omega$.
- (7) $R_{G1} = 120 \text{ k}\Omega$.

- (2) $R_{G1} = 56 \text{ k}\Omega$.
- $(5) \quad R_{G1} = 82 \; k\Omega.$
- (3) $R_{G1} = 68 \text{ k}\Omega$.
- (6) $R_{G1} = 100 \text{ k}\Omega$.

Fig.11 Drain current as a function of gate 1 (V_{GG}) and drain supply voltage; typical values.



 V_{DS} = 5 V; T_j = 25 °C; R_{G1} = 75 k Ω (connected to V_{GG}); see Fig.21.

- $(1) \quad V_{GG} = 5 \ V.$
- (4) $V_{GG} = 3.5 \text{ V}.$
- (2) $V_{GG} = 4.5 \text{ V}.$
- (5) $V_{GG} = 3 V$.
- (3) $V_{GG} = 4 V$.

Fig.12 Drain current as a function of gate 2 voltage; typical values.

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

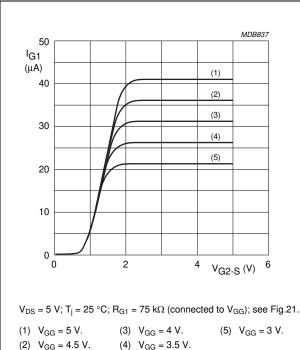
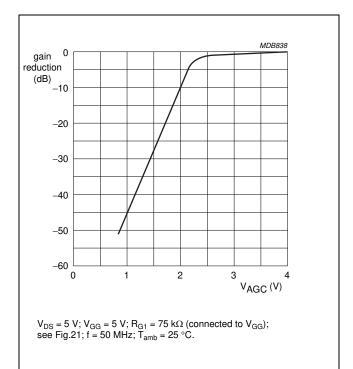
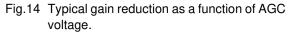
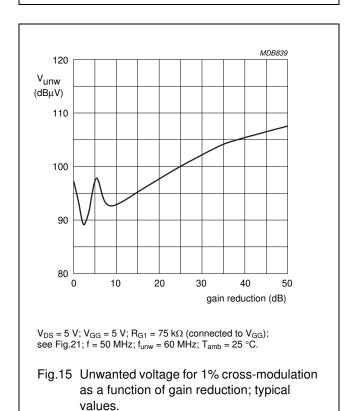
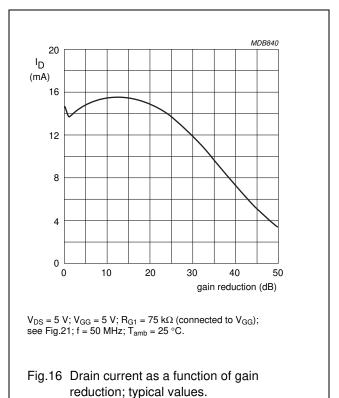


Fig.13 Gate 1 current as a function of gate 2 voltage; typical values.



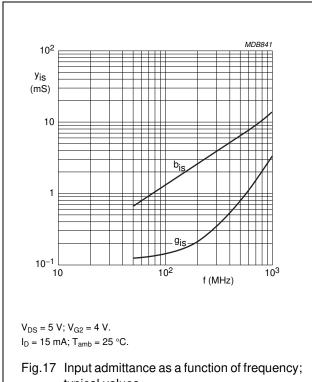




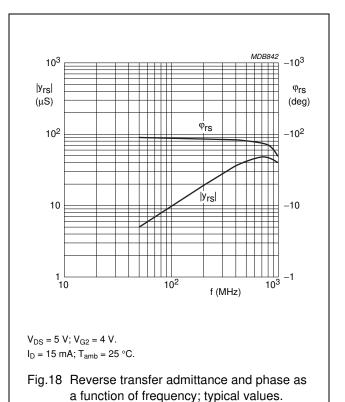


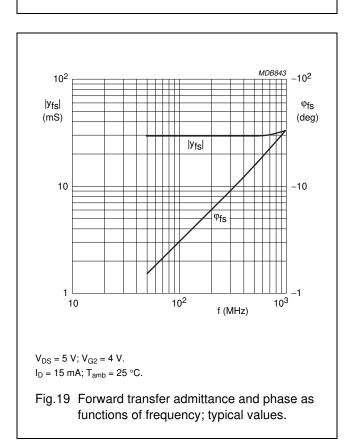
N-channel dual-gate MOS-FETs

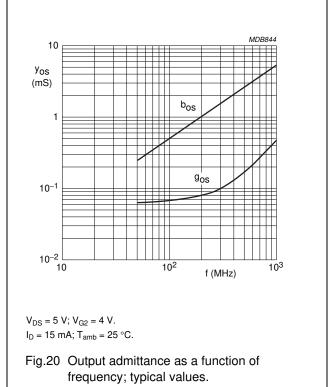
BF1211; BF1211R; BF1211WR



typical values.







N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

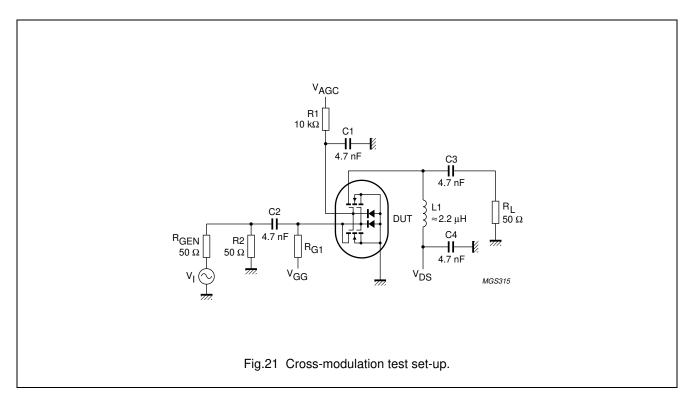


Table 1 Scattering parameters: $V_{DS} = 5 \text{ V}$; $V_{G2-S} = 4 \text{ V}$; $I_D = 15 \text{ mA}$; $T_{amb} = 25 ^{\circ}\text{C}$

	s ₁₁		s ₂₁	S ₂₁ S ₁₂			s ₂₂	
(MHz)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE ANGLE (ratio) (deg)		MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)
50	0.987	-3.86	2.928	175.8	0.0005	89.3	0.993	-1.58
100	0.985	-7.73	2.921	171.6	0.0010	86.9	0.993	-3.14
200	0.979	-15.25	2.807	163.2	0.0015	91.1	0.993	-6.31
300	0.965	-22.84	2.846	155.0	0.0028	77.4	0.988	-9.41
400	0.949	-30.15	2.784	146.7	0.0034	74.0	0.985	-12.48
500	0.929	-30.25	2.704	138.9	0.0037	71.4	0.981	-15.54
600	0.904	-44.24	2.639	130.9	0.0040	69.6	0.976	-18.59
700	0.876	-51.16	2.558	123.0	0.0039	69.0	0.971	-21.65
800	0.846	-58.16	2.486	115.1	0.0037	70.0	0.965	-24.27
900	0.816	-65.15	2.402	107.2	0.0032	74.5	0.960	-27.79
1000	0.791	-72.22	2.315	99.9	0.0028	87.1	0.956	-30.94

Table 2 Noise data: V_{DS} = 5 V; $V_{G2\text{-}S}$ = 4 V; I_D = 15 mA; T_{amb} = 25 °C

f	F _{min}	$\Gamma_{\mathbf{c}}$	ppt	R _n
(MHz)	(dB)	(ratio)	(Ω)	
400	0.9	0.693	16.75	29.85
800	1.3	0.707	37.33	29.90

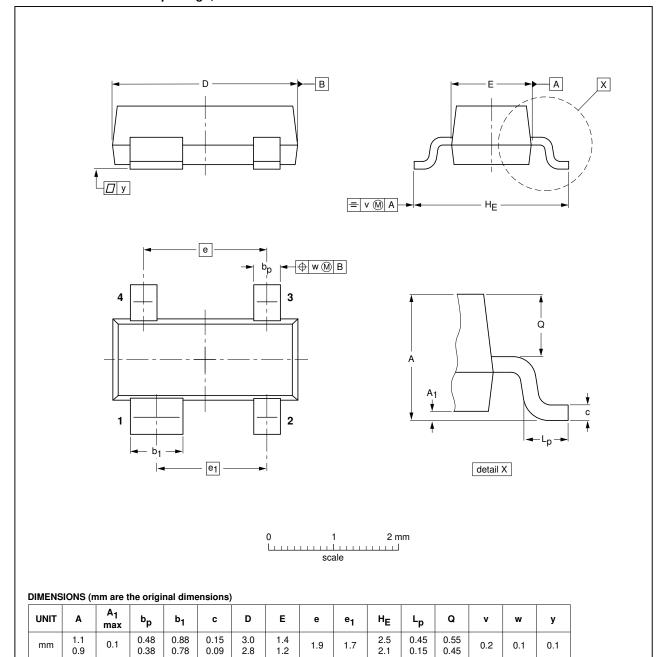
N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

PACKAGE OUTLINES

Plastic surface-mounted package; 4 leads

SOT143B



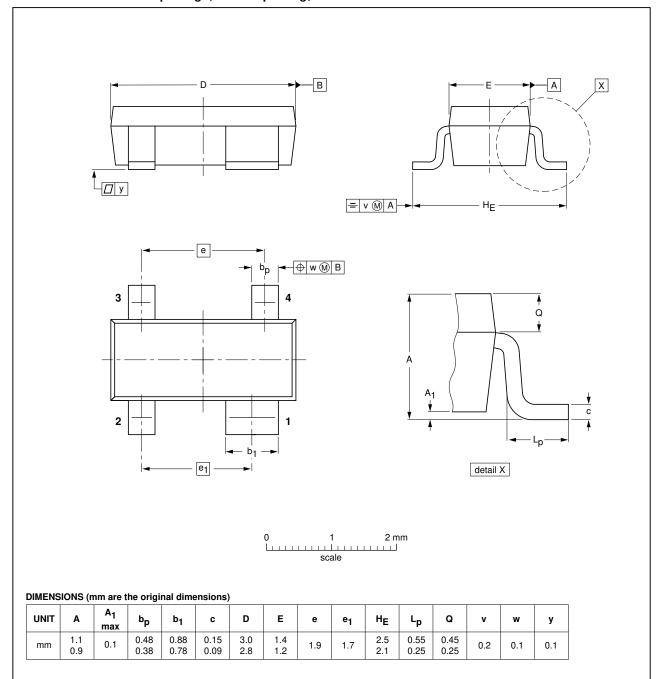
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VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT143B						-04-11-16- 06-03-16	

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

Plastic surface-mounted package; reverse pinning; 4 leads

SOT143R



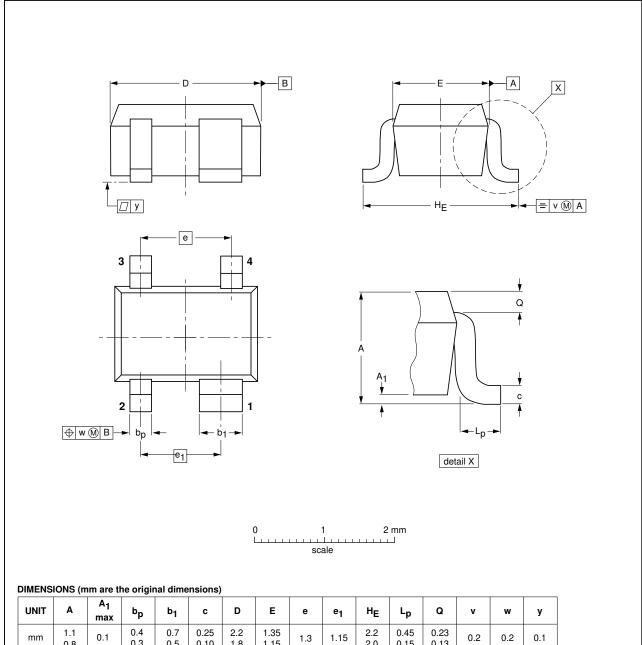
OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC JEDEC		JEITA		PROJECTION	ISSUE DATE	
SOT143R			SC-61AA		$ \ \ \bigoplus $	-04-11-16- 06-03-16	

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

Plastic surface-mounted package; reverse pinning; 4 leads

SOT343R



UNIT	A	A ₁ max	bp	b ₁	С	D	E	е	e ₁	HE	Lp	Q	v	w	у	
mm	1.1 0.8	0.1	0.4 0.3	0.7 0.5	0.25 0.10	2.2 1.8	1.35 1.15	1.3	1.15	2.2 2.0	0.45 0.15	0.23 0.13	0.2	0.2	0.1	

OUTLINE	REFERENCES				EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT343R						97-05-21 06-03-16

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

DATA SHEET STATUS

DOCUMENT STATUS(1)	PRODUCT STATUS ⁽²⁾	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet Production		This document contains the product specification.

Notes

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- 2. The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

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Customer notification

This data sheet was changed to reflect the new company name NXP Semiconductors, including new legal definitions and disclaimers. No changes were made to the technical content, except for package outline drawings which were updated to the latest version.

Contact information

For additional information please visit: http://www.nxp.com

For sales offices addresses send e-mail to: salesaddresses@nxp.com

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